

<b>Notice of Allowability</b>	<b>Application No.</b>	<b>Applicant(s)</b>	
	09/479,852	COSS JR. ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	Paul L Rodriguez	2125	

**-- The MAILING DATE of this communication appears on the cover sheet with the correspondenc address--**

All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. **THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS.** This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.

1. ☒ This communication is responsive to the papers filed 11/1/04.
2. ☒ The allowed claim(s) is/are 1-36.
3. ☒ The drawings filed on 07 January 2000 are accepted by the Examiner.
4. ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
  - a) ☐ All    b) ☐ Some\*    c) ☐ None    of the:
    1. ☐ Certified copies of the priority documents have been received.
    2. ☐ Certified copies of the priority documents have been received in Application No. \_\_\_\_\_.
    3. ☐ Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).

\* Certified copies not received: \_\_\_\_\_.

Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.  
**THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.**

5. ☐ A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.
6. ☐ CORRECTED DRAWINGS ( as "replacement sheets") must be submitted.
  - (a) ☐ including changes required by the Notice of Draftsperson's Patent Drawing Review ( PTO-948) attached
    - 1) ☐ hereto or 2) ☐ to Paper No./Mail Date \_\_\_\_\_.
  - (b) ☐ including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date \_\_\_\_\_.

Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).
7. ☐ DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.

**Attachment(s)**

- |   |  |
|---|--|
| <ol style="list-style-type: none"> <li>1. <input type="checkbox"/> Notice of References Cited (PTO-892)</li> <li>2. <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948)</li> <li>3. <input type="checkbox"/> Information Disclosure Statements (PTO-1449 or PTO/SB/08),<br/>Paper No./Mail Date _____</li> <li>4. <input type="checkbox"/> Examiner's Comment Regarding Requirement for Deposit<br/>of Biological Material</li> </ol> | <ol style="list-style-type: none"> <li>5. <input type="checkbox"/> Notice of Informal Patent Application (PTO-152)</li> <li>6. <input type="checkbox"/> Interview Summary (PTO-413),<br/>Paper No./Mail Date _____</li> <li>7. <input type="checkbox"/> Examiner's Amendment/Comment</li> <li>8. <input checked="" type="checkbox"/> Examiner's Statement of Reasons for Allowance</li> <li>9. <input type="checkbox"/> Other _____</li> </ol> |
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### DETAILED ACTION

1. The papers filed 11/1/04 have been received and considered. Claims 1-36 are presented for examination.

#### *Allowable Subject Matter*

2. Claims 1-36 are allowed.

3. The following is an examiner's statement of reasons for allowance:

While Flinchbaugh et al (U.S. Pat 4,861,419) discloses an apparatus and method of generating trace reports in a semiconductor fabrication process, employing fault detection, receiving specified data for trace data, the specified data including at least one of a parameter, a trigger, and a frequency for the trace data and formulating trace data reports, Turner et al (U.S. Pat 5,576,629) teaches fault detection control and reporting trace data, Miller et al (U.S. Pat 6,697,691) discloses a method and apparatus utilizing trace data in a semiconductor fabrication process, employing fault detection control, receiving specified data, trace data and reports, the specified data including at least one of a parameter, a trigger, and a frequency for the trace data, formulating reports and returning reports from a report generator, Coss, Jr. et al (U.S. Pat 6,465,263) disclose trace data in a semiconductor fabrication process employing fault detection control, receiving trace data including at least one of a parameter and a trigger, requesting the trace data, formulating the trace data and returning trace data, Jang et al (U.S. Pat 6,438,441) discloses generating trace data for a semiconductor fabrication process, receiving trace data and requesting trace data, Ogushi et al (U.S. Pat 6,385,497) discloses dynamically generating reports in a semiconductor fabrication process employing fault detection control, receiving specified

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data for a report, the data including at least one of a parameter, a trigger, and a frequency for the report and formulating the report, and Wang et al (U.S. Pat 5,859,964) teaches dynamically generating reports in a semiconductor fabrication process employing fault detection, receiving specified data for a report, the specified data including at least one of a parameter, a trigger, and a frequency for the report, generating a request to a report generator, formulating data reports responsive to the request, and returning the report. None of these reference taken either alone or in combination with the prior art of record disclose a method for dynamically generating trace data reports in a semiconductor fabrication process or a semiconductor fabrication processing system specifically, including:

(claim 1, 7, 15) “a method of receiving specified data for a trace data report, automatically generating from a fault detection controller a request to a report generator for the trace data report”,

(claim 23, 30) “a fabrication tool capable of providing a trace data report, a fault detection controller capable of automatically generating a request for a trace data report, a report generator capable of requesting the trace data report from the fabrication tool and providing the trace data report”,

in combination with the remaining elements and features of the claimed invention. It is for these reasons that the applicant’s invention defines over the prior art of record.

4. Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue

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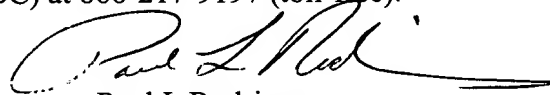
fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

***Conclusion***

5. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Paul L Rodriguez whose telephone number is (571) 272-3753. The examiner can normally be reached on 6:00 - 4:30 T-F.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Leo P Picard can be reached on (571) 272-3749. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).



Paul L Rodriguez  
Primary Examiner  
Art Unit 2125

PLR  
12/16/04